

This Listing of Claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

1. (Currently Amended) A nonvolatile semiconductor memory device comprising:
a memory array ~~composed of~~ comprising a plurality of floating-gate field-effect ~~transistor~~
transistors connected to a row line and a column line and disposed in a matrix configuration, the
transistors being connected to corresponding row lines and column lines, at least one of the
transistors comprising the floating-gate field-effect transistor including
a source and a drain which are formed inside a P-type well ~~provided~~ formed inside an N-
type well formed on a semiconductor substrate,
a floating gate formed ~~[[over]]~~ above a portion of the semiconductor substrate between
the source and the drain with an insulating film interposed ~~therebetween~~ between the floating
gate and said portion of the semiconductor substrate, and
a control gate formed on the floating gate with ~~[[a]]~~ another insulating film interposed
therebetween;
a first voltage application ~~means for~~ circuit applying a first voltage to the P-type well
when an erasing pulse is applied; and
a second voltage application ~~means for~~ circuit applying a second voltage to the N-type
well when ~~[[an]]~~ the erasing pulse is applied.

2. (Currently Amended) The nonvolatile semiconductor memory device ~~as defined in Claim of claim 1~~, wherein the first voltage and the second voltage are positive voltages, and the second voltage is higher than the first voltage.

3. (Currently Amended) The nonvolatile semiconductor memory device ~~as defined in Claim of claim 1~~, wherein the first voltage application ~~means is~~ circuit comprises a first high-voltage pumping circuit for generating the first voltage, and the second voltage application ~~means is~~ circuit comprises a second high-voltage pumping circuit for generating the second voltage.

4. (Currently Amended) The nonvolatile semiconductor memory device ~~as defined in Claim of claim 1~~, wherein the first voltage application ~~means is~~ circuit comprises a first high-voltage pumping circuit for generating the first voltage, and the second voltage application ~~means is~~ circuit comprises an auxiliary pumping circuit for ~~generating the second voltage higher than raising the first voltage by receiving to generate the first second~~ voltage.

5. (Currently Amended) The nonvolatile semiconductor memory device ~~as defined in Claim of claim 1~~, wherein the second voltage application ~~means is~~ circuit comprises a high-voltage pumping circuit for generating the second voltage ~~higher than the first voltage~~, and the first voltage application ~~means is~~ circuit comprises a regulator circuit for ~~generating the first voltage lower than lowering the second voltage by receiving to generate the second first~~ voltage.